

Search Notes

Application/Control No.

10/812,526

Examiner

David J. Makiya

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2875

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search in EAST attached	4/27/2006	DJM